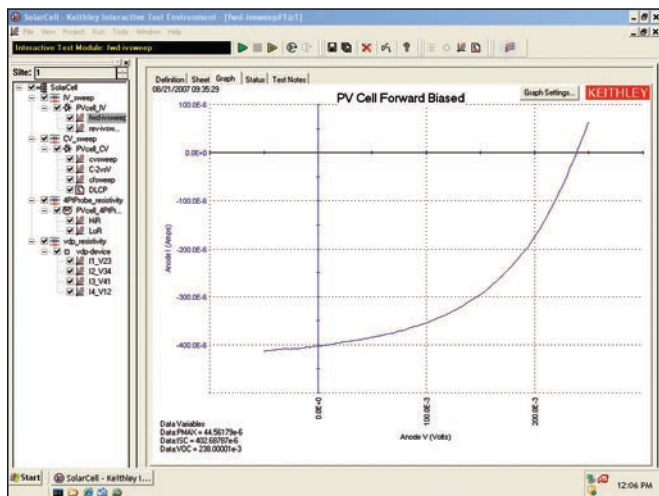
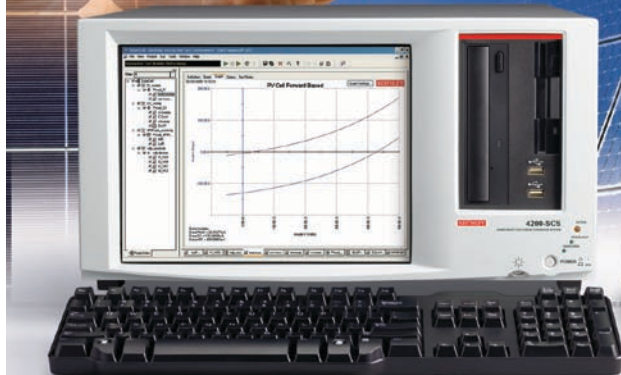


# Simplify Your Solar Cell Testing with Keithley's Precision Measurement Solutions



Keithley's solutions for solar cell I-V and C-V characterization provide the most accurate measurements available without the hassles of integrating separate instruments or writing complicated programs.

Electrical characterization of a variety of solar cell (Photovoltaic) technologies, including:

- Mono Crystalline Si
- Poly Crystalline Si
- Amorphous Si
- CIGS
- CdTe
- Polymer Organic

Measurement of key parameters including:

- Open circuit voltage ( $V_{oc}$ )
- Short circuit current ( $I_{sc}$ )
- Maximum power output ( $P_{max}$ )
- Voltage at  $P_{max}$  ( $V_{max}$ )
- Fill factor ( $ff$ )
- Series resistance ( $R_s$ )
- Shunt resistance ( $R_{sh}$ )
- Conversion efficiency ( $\eta$ )
- Doping density ( $N$ )
- Cell resistivity
- Defect density

## MODEL 4200-SCS SEMICONDUCTOR CHARACTERIZATION SYSTEM

- Fully integrated I-V and C-V turn key solution with intuitive graphical user interface
- Built-in libraries for extracting key cell parameters, and advanced analytical and formulation tools

## SERIES 2400 OR 2600A SOURCEMETER® INSTRUMENTS

- 4-quadrant design provides both source and sink capability for complete I-V
- All-in-one solution for I-V characterization with the combined functionality of a precision power supply, high precision DMM, and electronic load